

SPECIFICATION

(Reference sheet)

- Supplier : Samsung electro-mechanics
- Product : Multi-layer Ceramic Capacitor

- Samsung P/N : **CL31B102K1FSFNE**
- Description : **CAP, 1nF, 1000V, ±10%, X7R, 1206**

A. Samsung Part Number

CL 31 B 102 K 1 F S F N E
 ① ② ③ ④ ⑤ ⑥ ⑦ ⑧ ⑨ ⑩ ⑪

① Series	Samsung Multi-layer Ceramic Capacitor		
② Size	1206 (inch code)	L : 3.20 ± 0.15 mm	W : 1.60 ± 0.15 mm
③ Dielectric	X7R	⑧ Inner electrode	Ni
④ Capacitance	1 nF	Termination	Soft termination
⑤ Capacitance tolerance	±10 %	Plating	Sn 100% (Pb Free)
⑥ Rated Voltage	1000 V	⑨ Product	Product for POWER application
⑦ Thickness	1.25 ± 0.15 mm	⑩ Special	Reserved for future use
		⑪ Packaging	Embossed Type, 7" reel

B. Structure & Dimension



Samsung P/N	Dimension(mm)			
	L	W	T	BW
CL31B102K1FSFNE	3.20 ± 0.15	1.60 ± 0.15	1.25 ± 0.15	0.50 ± 0.30

C. Samsung Reliability Test and Judgement Condition

	Judgement	Test condition
Capacitance	Within specified tolerance	1kHz ±10% / 1.0±0.2Vrms
Tan δ (DF)	0.025 max.	*A capacitor prior to measuring the capacitance is heat treated at 150 °C+0/-10 °C for 1hour and maintained in ambient air for 24±2 hours.
Insulation Resistance	10,000Mohm or 500Mohm×μF Whichever is smaller	500±50 Vdc 60±5 sec.
Appearance	No abnormal exterior appearance	Microscope (×10)
Withstanding Voltage	No dielectric breakdown or mechanical breakdown	120% of the rated voltage
Temperature Characteristics	X7R (From -55°C to 125°C, Capacitance change should be within ±15%)	
Adhesive Strength of Termination	No peeling shall be occur on the terminal electrode	500g-f, for 10±1 sec.
Bending Strength	Capacitance change : within ±12.5%	Bending to the limit (1mm) with 1.0mm/sec.
Solderability	More than 95% of terminal surface is to be soldered newly	SnAg3.0Cu0.5 solder 245±5°C, 3±0.3sec. (preheating : 80~120°C for 10~30sec.)
Resistance to Soldering Heat	Capacitance change : within ±7.5% Tan δ, IR : initial spec.	Solder pot : 270±5°C, 10±1sec.
Vibration Test	Capacitance change : within ± 5% Tan δ, IR : initial spec.	Amplitude : 1.5mm From 10Hz to 55Hz (return : 1min.) 2hours × 3 direction (x, y, z)
High Temperature Resistance	Capacitance change : within ±12.5% Tan δ : 0.05 max IR : 1,000Mohm or 50Mohm × μF Whichever is smaller	With 100% of the rated voltage Max. operating temperature 1,000+48/-0hrs
Temperature Cycling	Capacitance change : within ±7.5% Tan δ, IR : initial spec.	1 cycle condition Min. operating temperature → 25°C → Max. operating temperature → 25°C 5 cycle test

※ The reliability test condition can be replaced by the corresponding accelerated test condition.

D. Recommended Soldering method :

Reflow (Reflow Peak Temperature :250 °C, 6 sec max.)



Product specifications included in the specifications are effective as of March 1, 2013.

Please be advised that they are standard product specifications for reference only.

We may change, modify or discontinue the product specifications without notice at any time.

So, you need to approve the product specifications before placing an order.

Should you have any question regarding the product specifications,

please contact our sales personnel or application engineers.

- Disclaimer & Limitation of Use and Application -

The products listed in this Specification sheet are **NOT** designed and manufactured for any use and applications set forth below.

Please note that any misuse of the products deviating from products specifications or information provided in this Spec sheet may cause serious property damages or personal injury.

We will **NOT** be liable for any damages resulting from any misuse of the products, specifically including using the products for high reliability applications as listed below.

If you have any questions regarding this 'Limitation of Use and Application', you should first contact our sales personnel or application engineers.

- ① Aerospace/Aviation equipment
- ② Automotive or Transportation equipment (vehicles, trains, ships, etc)
- ③ Medical equipment
- ④ Military equipment
- ⑤ Disaster prevention/crime prevention equipment
- ⑥ Any other applications with the same as or similar complexity or reliability to the applications set forth above.